



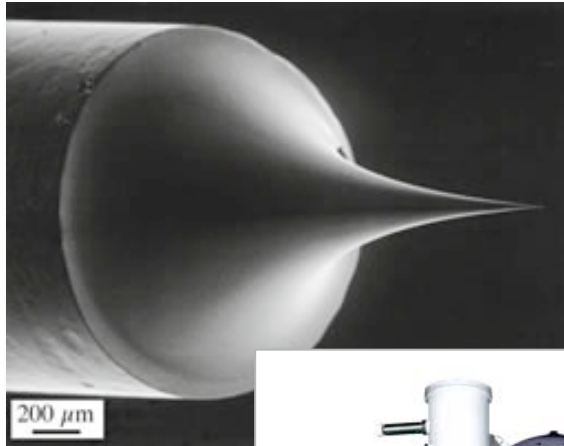
S. Tsujino

# Focused tips arrays for production of cold electron beams

**2016-10-19 Photocathode Physics for Photoinjectors (P3) 2016**

Thomas Jefferson National Accelerator Facility, Newport News, Virginia USA

# Field emitters...for accelerators?



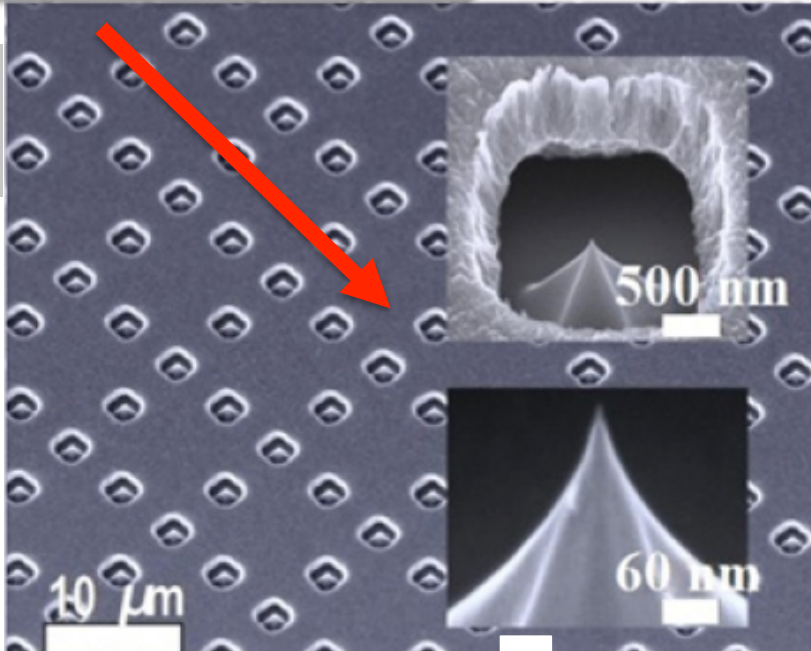
FEG TEM: JEOL JEM 3200FS

- Nanometer tip
- Small electron energy spread
- High current density
- Coherent e-source for high resolution app.

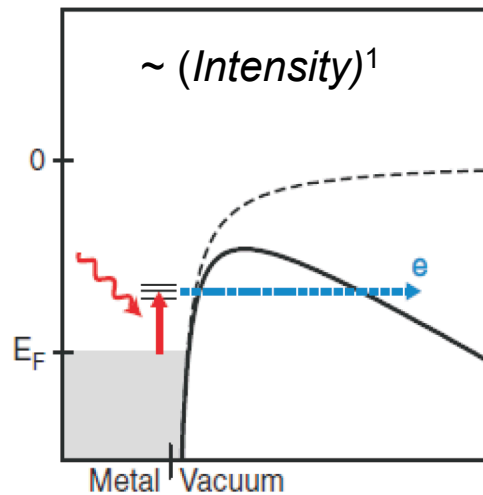
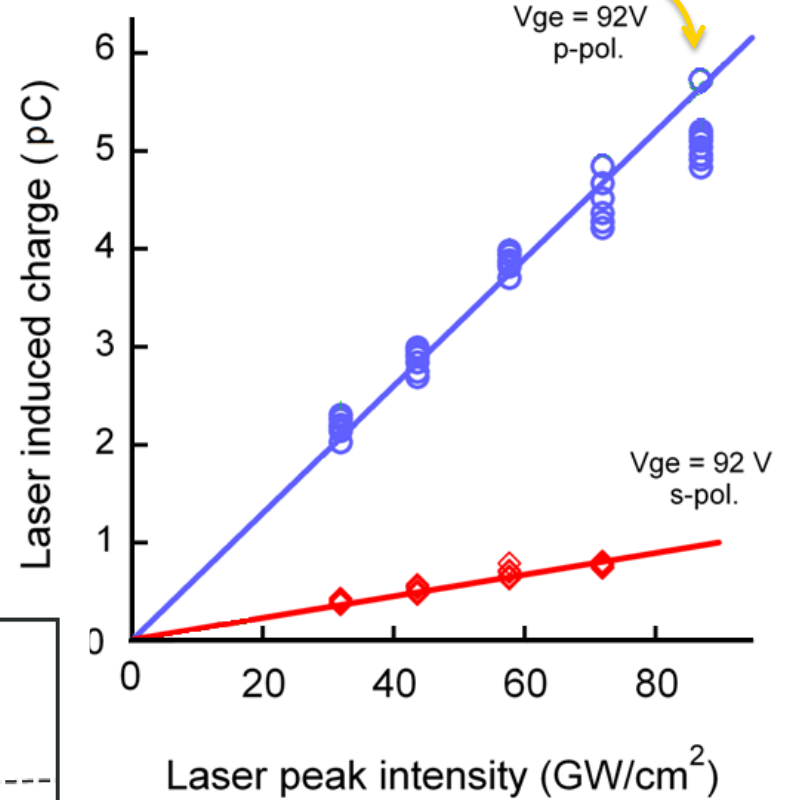
# Field emitters...for accelerators?

800 nm (1.6 eV), 50 fs

5 pC,  $10^7 e^-$ , ~100 A?

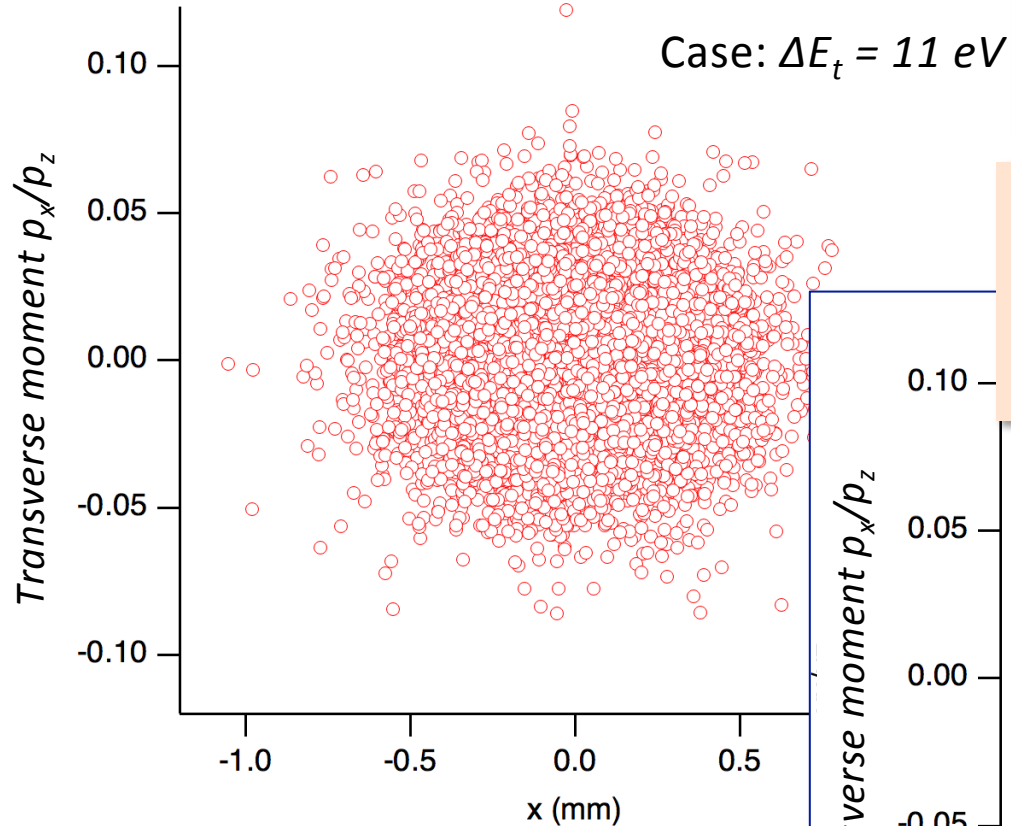


Single-gate FEA,  $10^5$ -tip

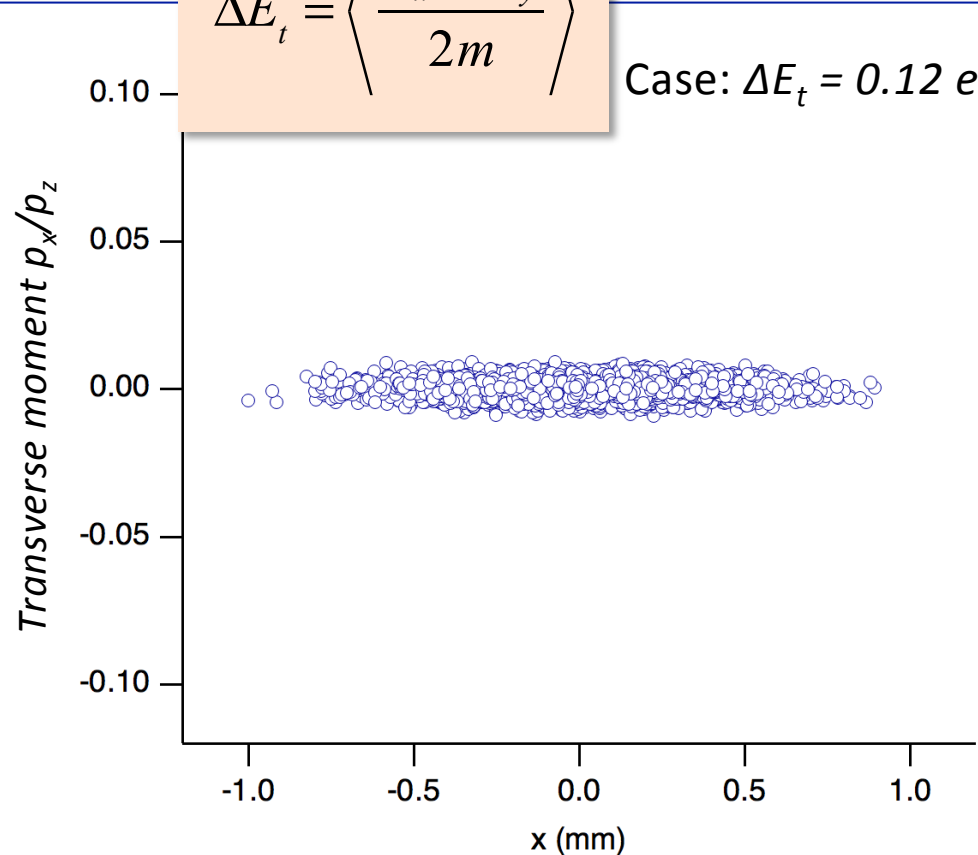


## Emittance reduction

$$\begin{aligned}\varepsilon_x &= \sqrt{\langle x^2 \rangle \langle (p_x / mc)^2 \rangle - \langle x(p_x / mc) \rangle^2} \\ &= \beta\gamma \sqrt{\langle x^2 \rangle \langle x'^2 \rangle - \langle xx' \rangle^2}\end{aligned}$$



$$\Delta E_t = \left\langle \frac{p_x^2 + p_y^2}{2m} \right\rangle$$

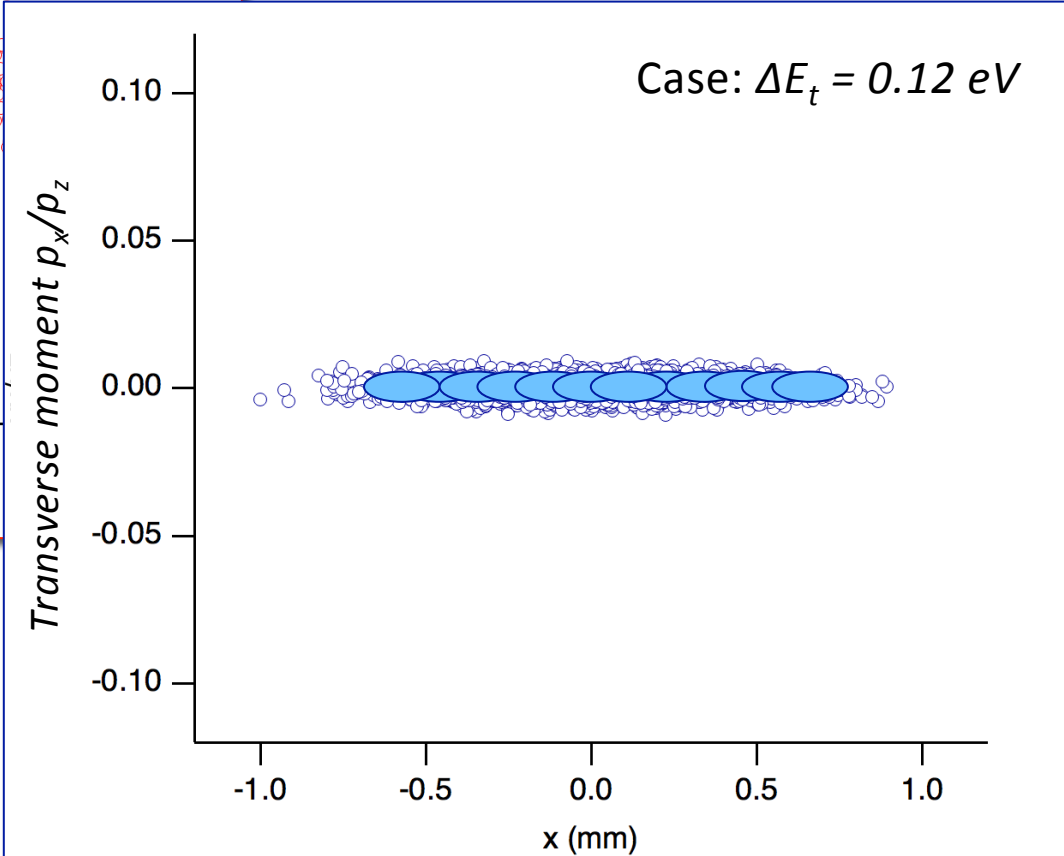
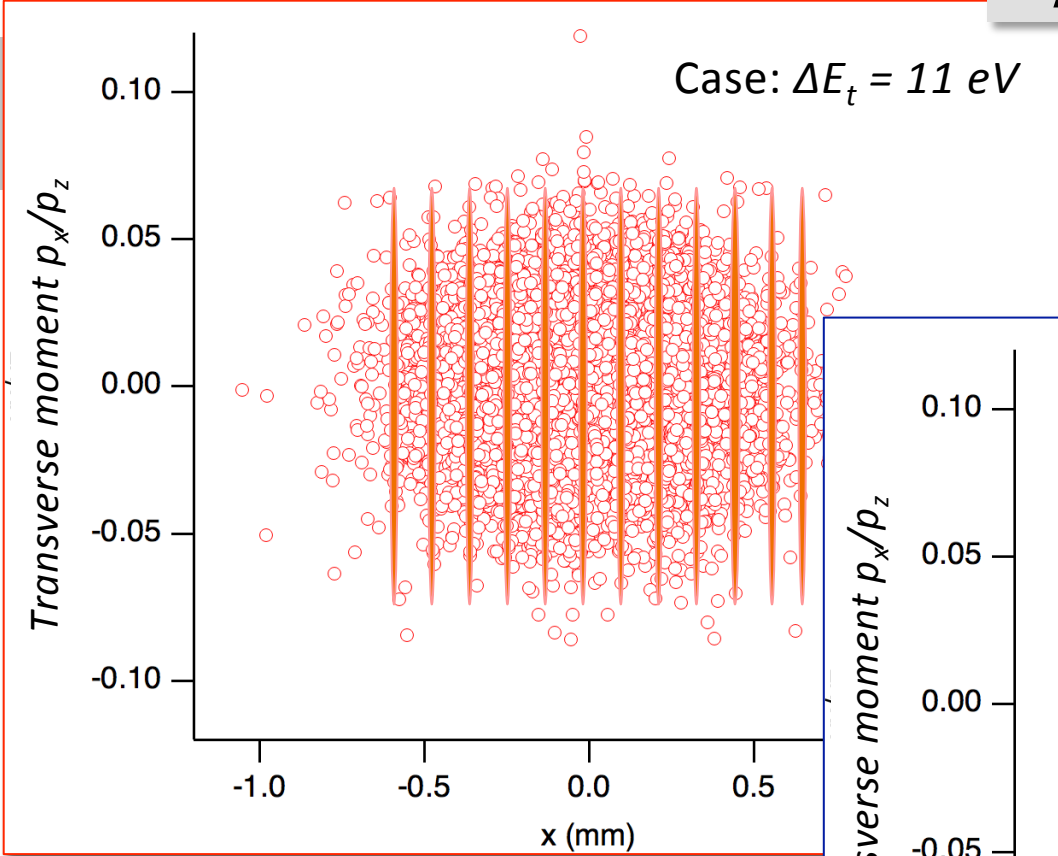
Case:  $\Delta E_t = 0.12 \text{ eV}$ 

# Emittance reduction

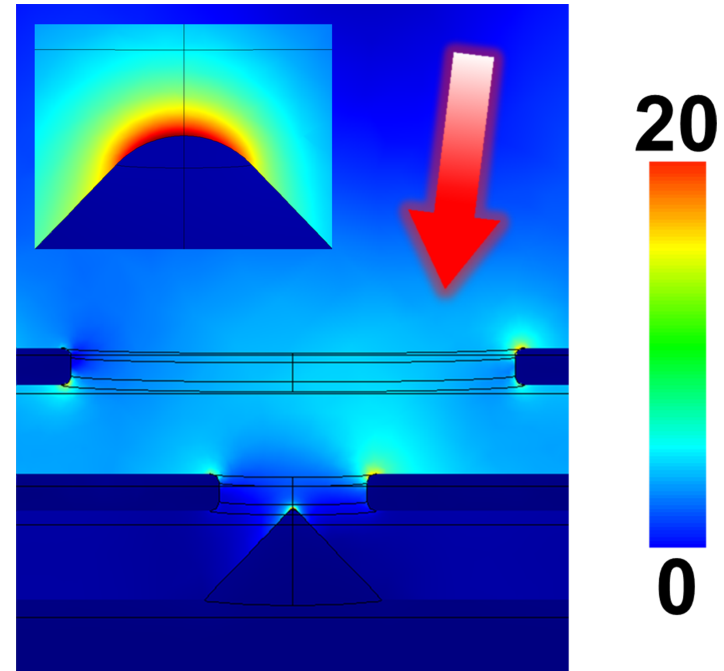
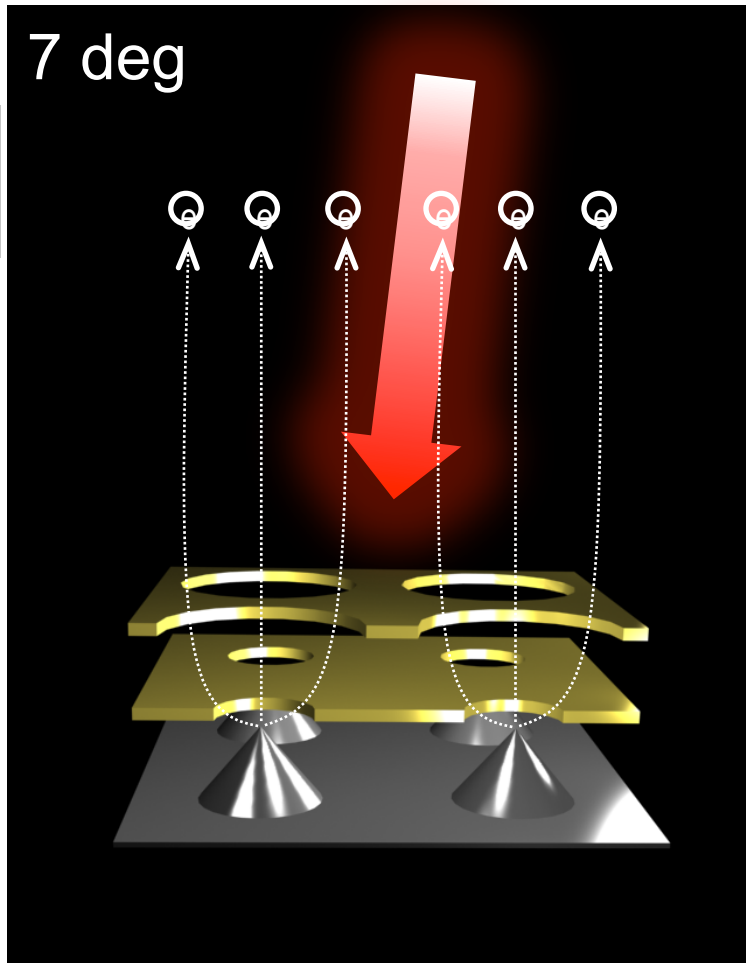
$$\varepsilon_x = \sqrt{\langle x^2 \rangle \langle (p_x / mc)^2 \rangle - \langle x(p_x / mc) \rangle^2}$$

$$= \beta\gamma \sqrt{\langle x^2 \rangle \langle x'^2 \rangle - \langle xx' \rangle^2}$$

$$\Delta E_t = \left\langle \frac{p_x^2 + p_y^2}{2m} \right\rangle$$



# SPP-enhanced tip-laser coupling

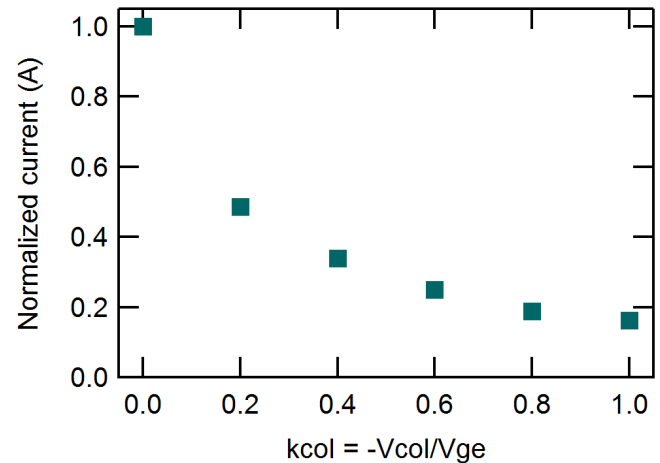
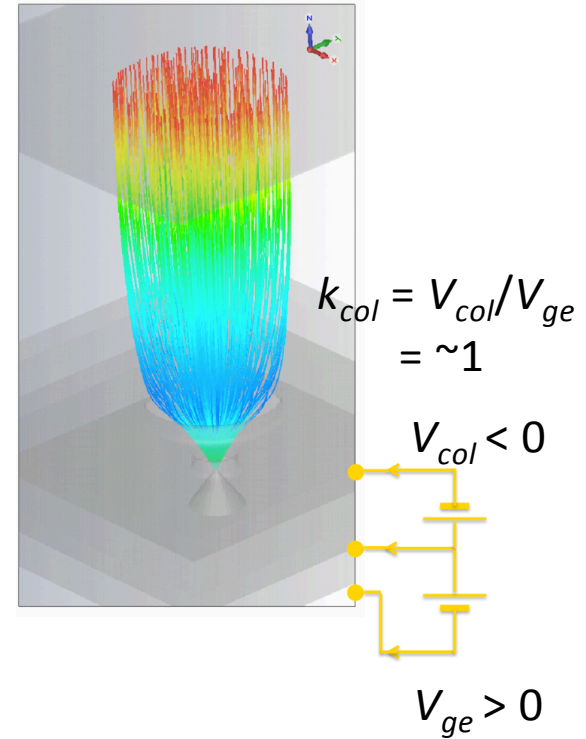
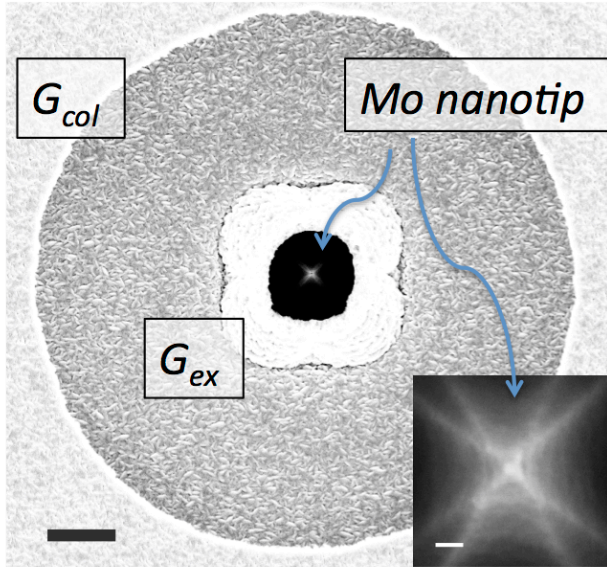
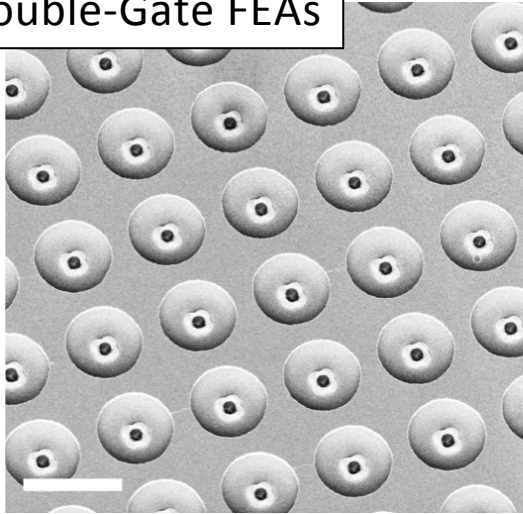


- $10^6$  emitters, 1  $\mu\text{m}$ -pitch, NIR (800 nm) excitation
- Copper double-gate struc. to support surface plasmon polariton => enhanced tip excitation
- Predicted electron yield  $\sim 10^{-5}$ ,
- Requiring NIR pulse energies of  $\sim 25 \mu\text{J}$  for 200 pC.

(APL 2008/2009/2011-2, SciRep 2012, APEX 2013, JVST2015)

# Field emitters...for accelerators?

Double-Gate FEAs



## I. Challenges of double-gate FEAs

- Quenching of emission current by “collimation”  
=> “engineered” gate structure  
(APL 2011, JAP 2012/2013, JVST 2015-1/2015-2)
- Non-uniformity of the tip-sharpness  
=> Ne conditioning for selective blunting (APL 2011-1, JAP 2013)

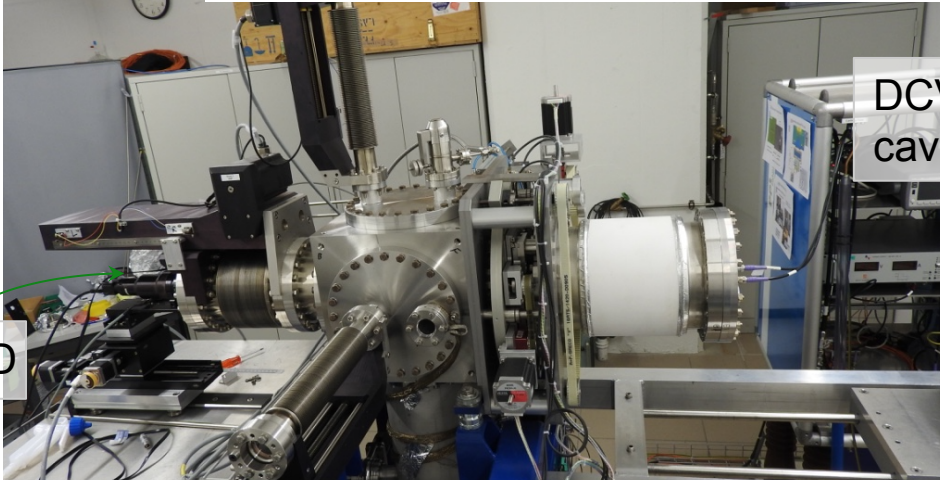
## II. Requirement for accelerator applications?

- High current & short pulse  
=> Field emission of NIR exited (single) FEA,  
w/surface-plasmon enhancement  
(APL 2008/2009/2011-2, SciRep 2012, APEX 2013, JVST2015)
- High gradient compatibility  
=> Tested (w/single-gate FEA) up to  $\sim 30$  MV/m (JVST 2011, PoP 2011)
- Emittance => Is it small?



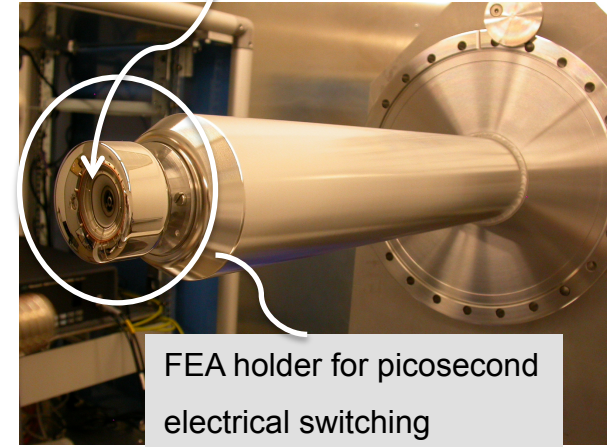
# FEA characterization in a dc gun

FEA sees the acceleration from the 4 mm-opening of the holder

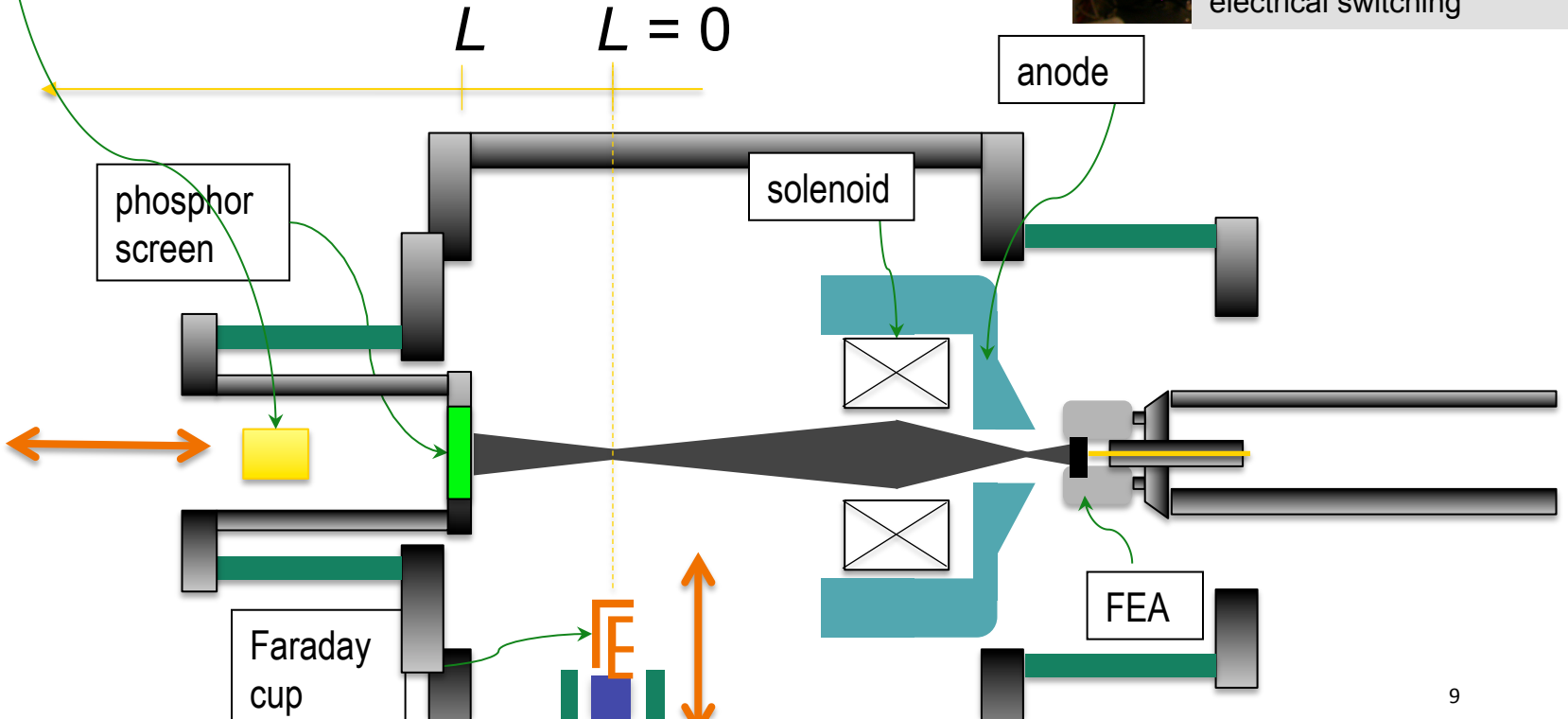


DCV cabinet

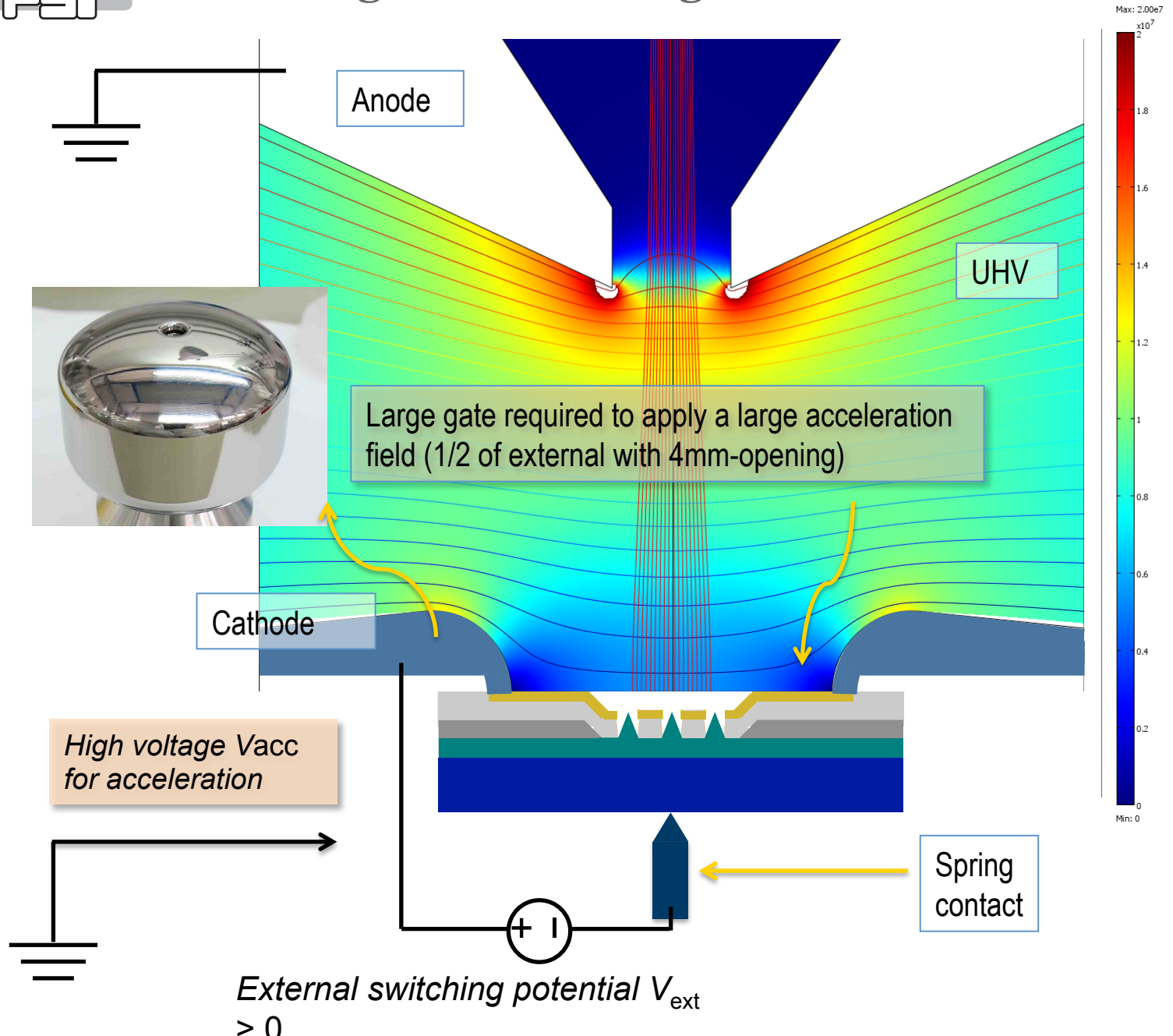
CCD



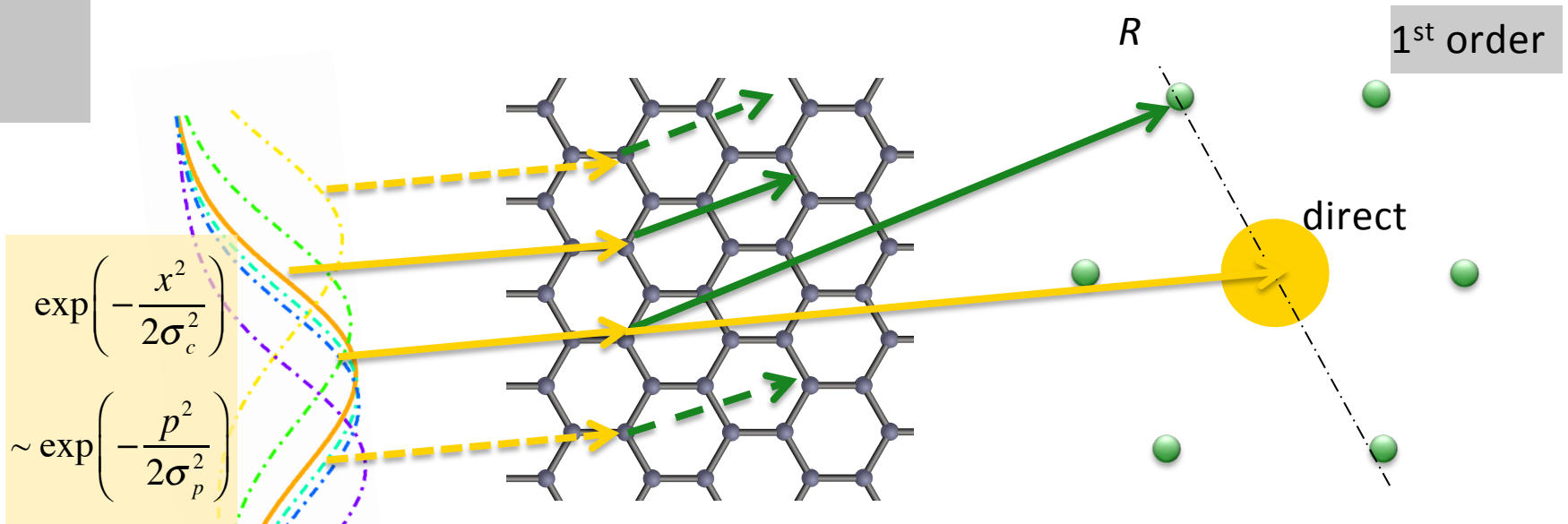
FEA holder for picosecond electrical switching



# FEA integration to DC gun

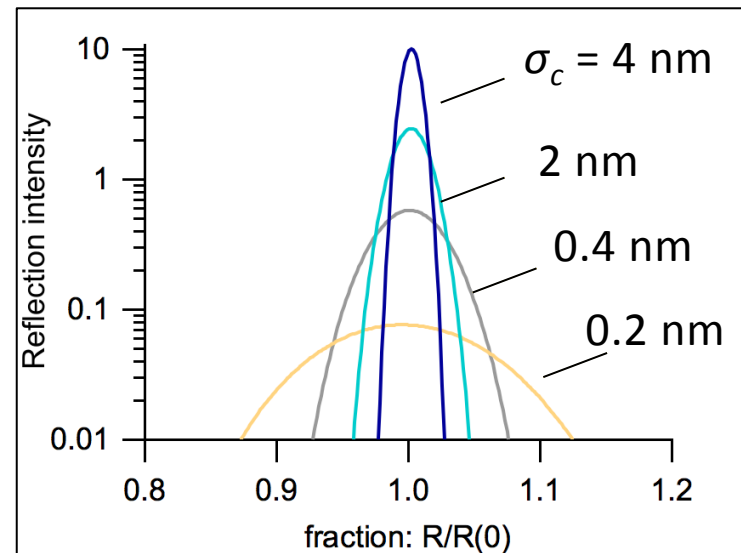


# Is FEA beam coherent?...test with diffraction

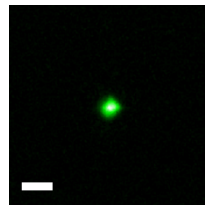
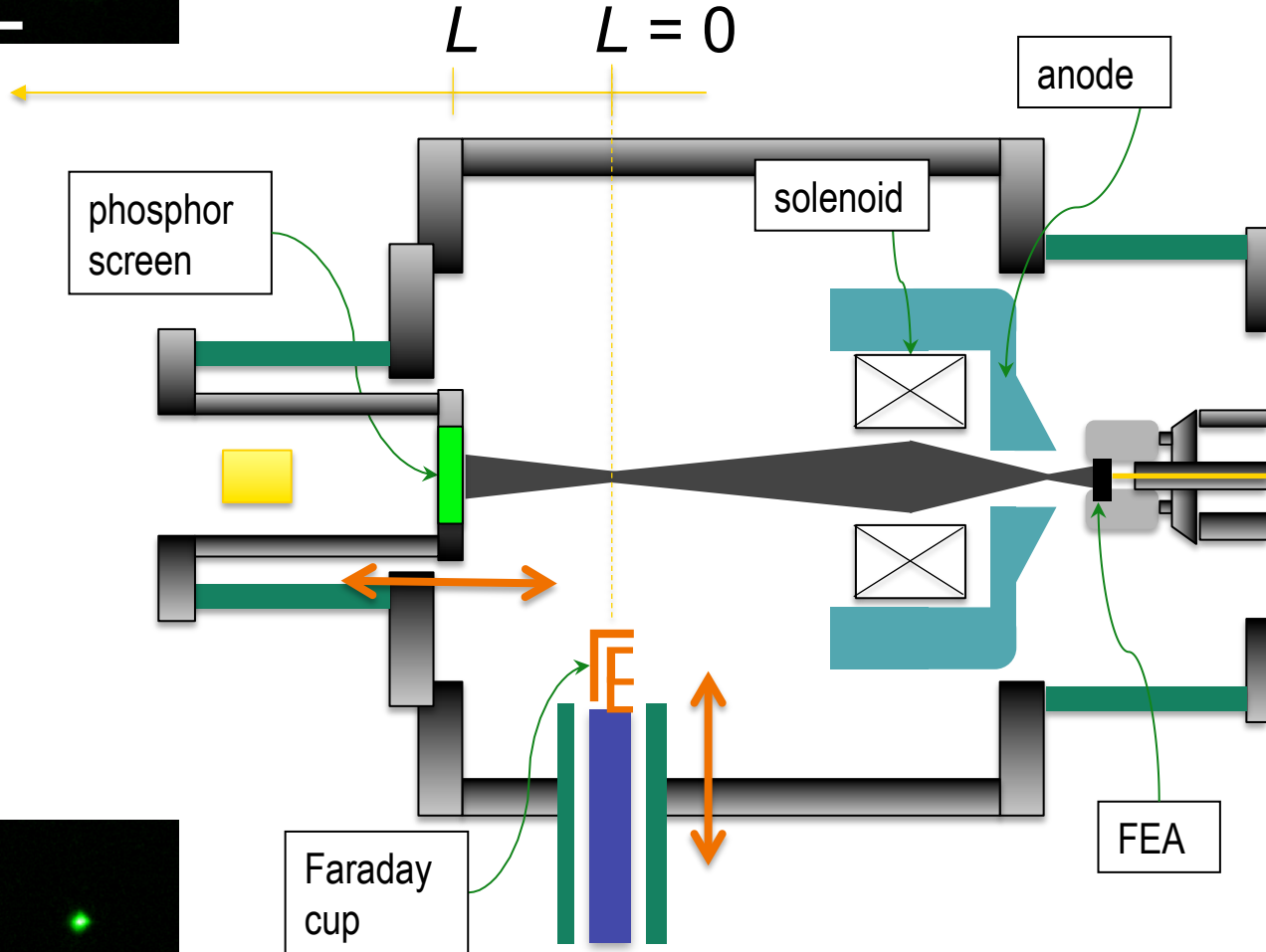
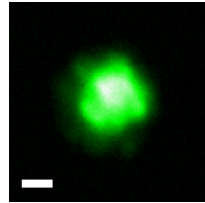


Use graphene as coherence ruler:

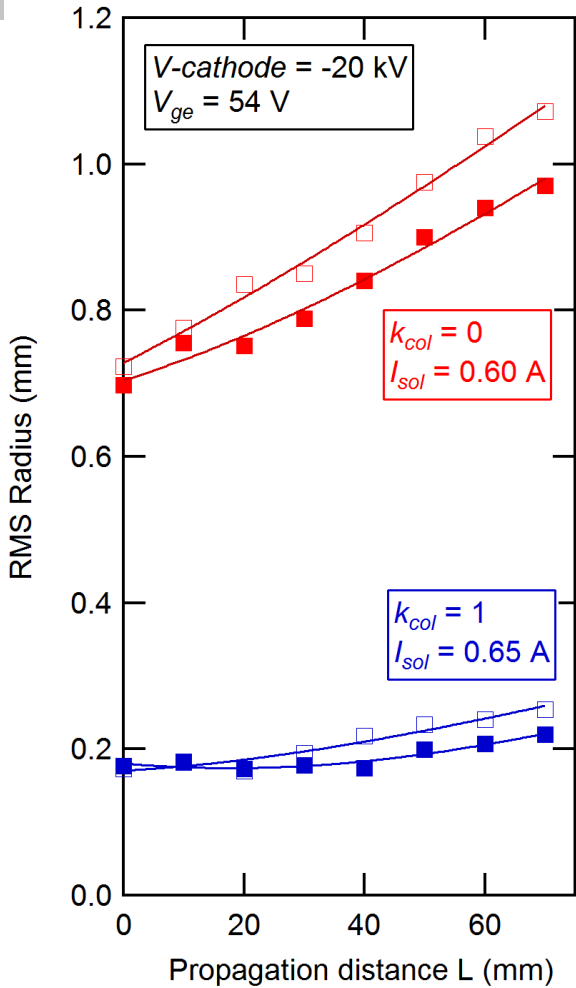
*Longer coherence length*  
 ( $\sigma_c = rms$  coherence length)  
 => Sample more lattices  
 => **Sharper diffraction spot**



Focused beam (by solenoid)  
[un-collimated,  $k_{col} = 0$ ]



Focused beam  
[collimated,  $k_{col} = 1$ ]



## Reduction of transverse emittance

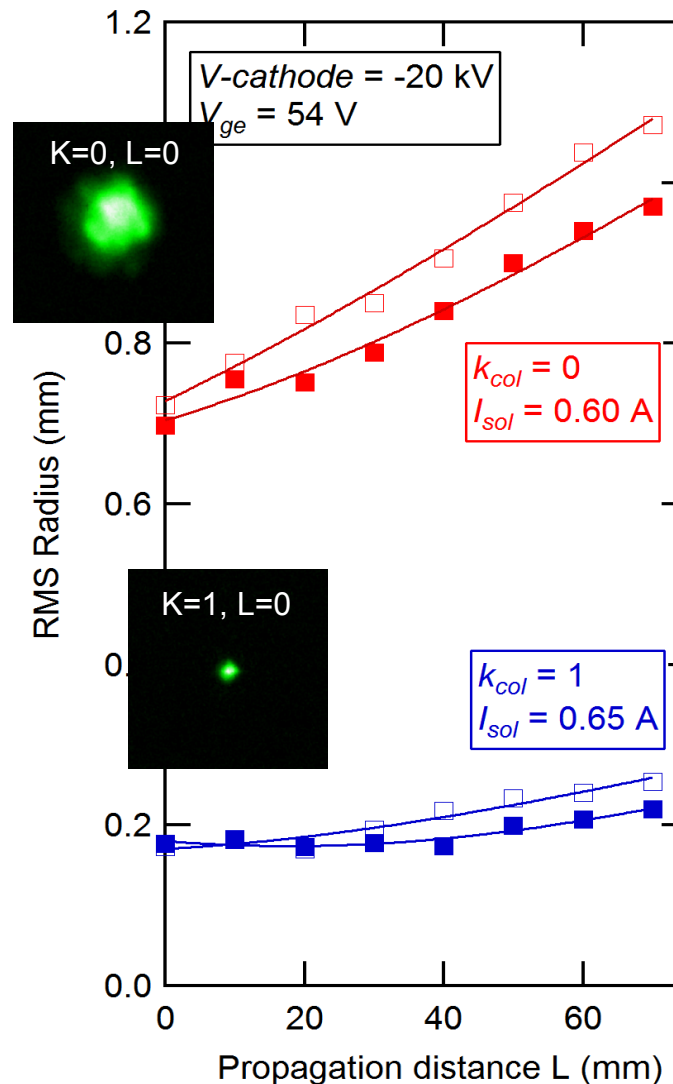
$$\sigma_x^2(L) = \langle x^2 \rangle_0 + 2 \langle xx' \rangle_0 L + \langle x'^2 \rangle_0 L^2$$

$$\varepsilon_x = \beta \gamma \sqrt{\langle x^2 \rangle \langle x'^2 \rangle - \langle xx' \rangle^2}$$

$$\gamma = 1 / \sqrt{1 - \beta^2} = 1.04 \quad (20 \text{ kV})$$

$$\beta = v_{\text{long}} / c \sim 0.27$$

$$\varepsilon_x = R_{\text{rms}} (v_{x,\text{rms}} / c)$$



Uncollimated  
Beam (k=0)

$$\varepsilon = 1.2 \text{ } \mu\text{m}$$

Collimated beam  
(k=1)

$$\varepsilon = 0.1 \text{ } \mu\text{m}$$

# Reduction of transverse emittance

$$\sigma_x^2(L) = \langle x^2 \rangle_0 + 2 \langle xx' \rangle_0 L + \langle x'^2 \rangle_0 L^2$$

$$\epsilon_x = \beta \gamma \sqrt{\langle x^2 \rangle \langle x'^2 \rangle - \langle xx' \rangle^2}$$

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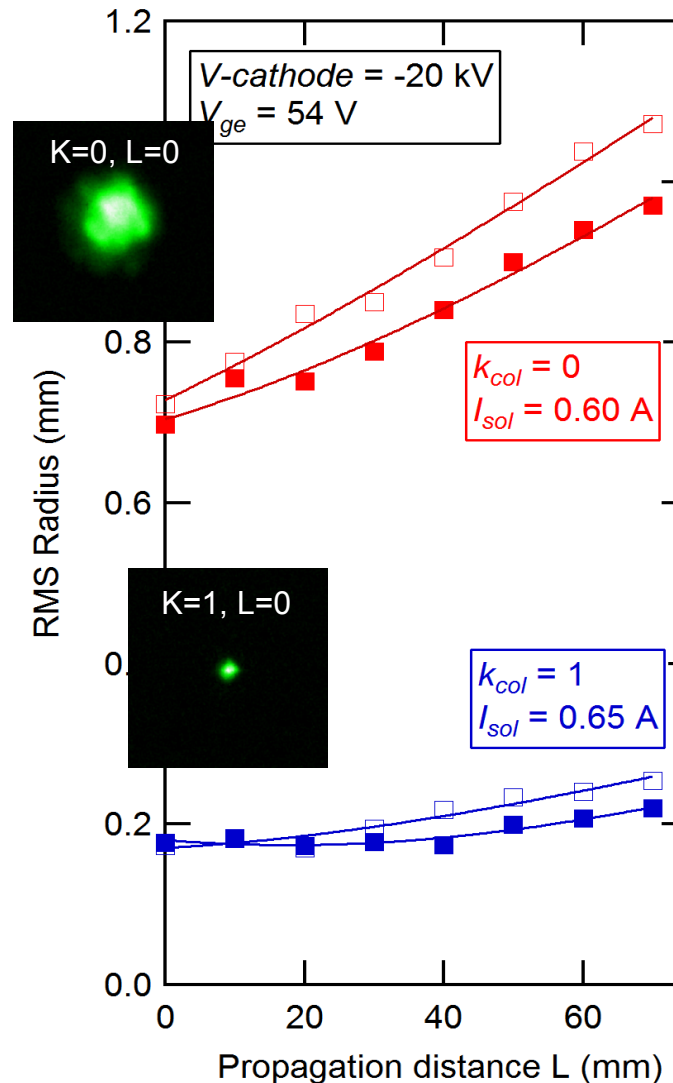
$$\epsilon_x = R_{rms} (v_{x,rms} / c)$$

$$E_t = \frac{m}{2} (v_{x,rms}^2 + v_{y,rms}^2)$$

11.8 eV (k = 0)

0.13 ± 0.06 eV (k = 1)

$\epsilon/\sigma = 0.5 \text{ } \mu\text{m/mm-rms}$

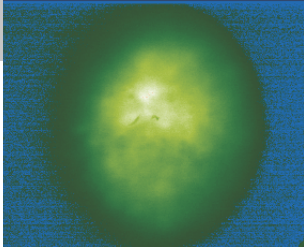


Uncollimated  
Beam (k=0)  
 $\epsilon = 1.2 \text{ } \mu\text{m}$

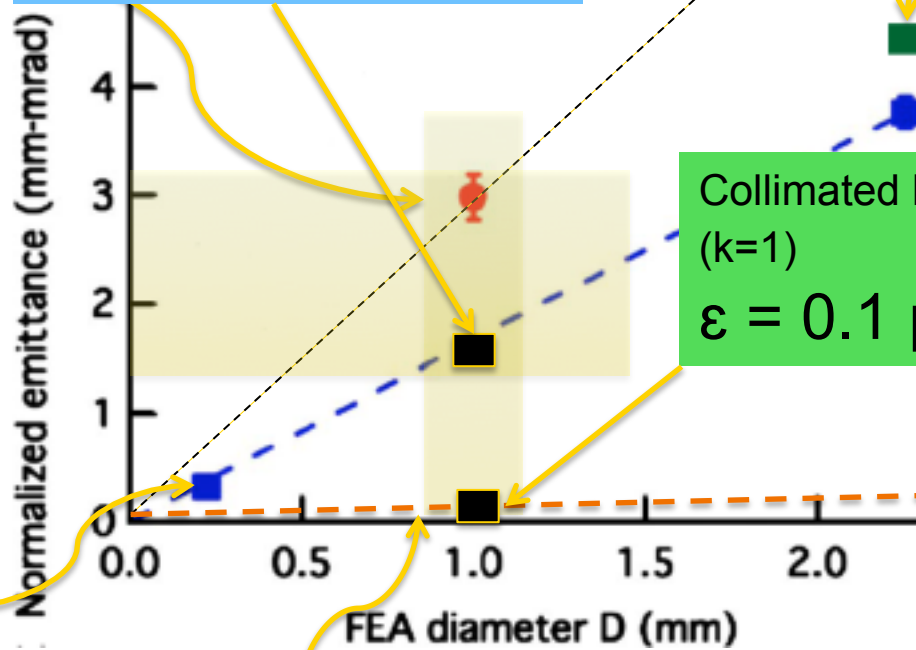
Collimated beam  
(k=1)  
 $\epsilon = 0.13 \text{ } \mu\text{m}$

# Reduced emittance: Double-gate FEA?

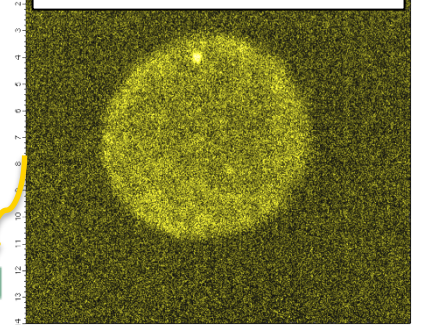
Spindt-FEA



Double-gate FEA  
Uncollimated beam ( $k=0$ )  
 $\epsilon = 1.2 \mu\text{m}$

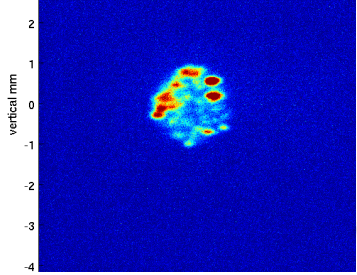


FEA3: Ne-conditioned

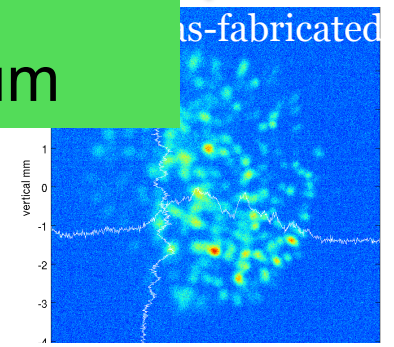


Collimated beam  
( $k=1$ )  
 $\epsilon = 0.1 \mu\text{m}$

FEA2: as-fabricated



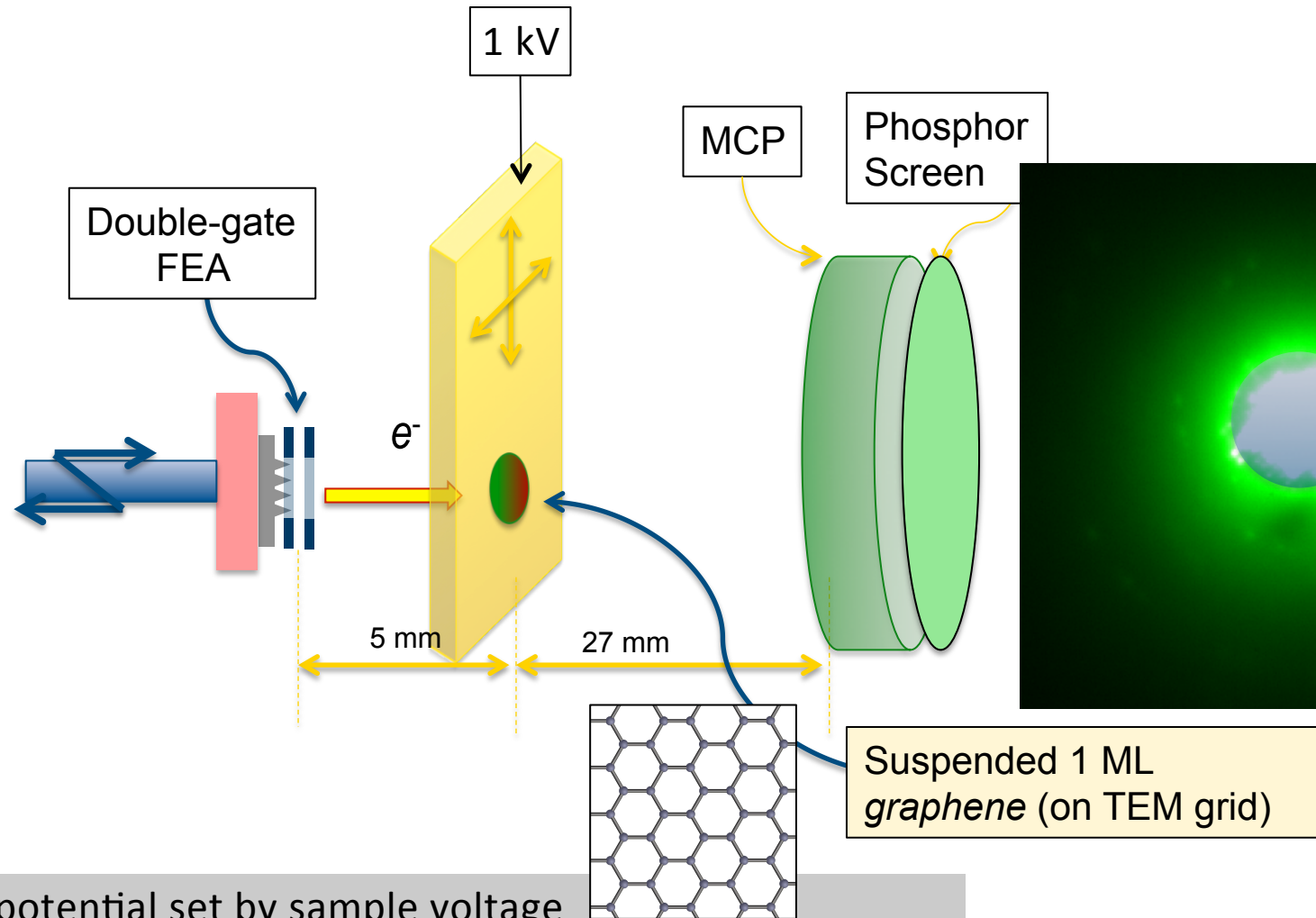
as-fabricated



Target: below  $\sim 0.1 \mu\text{m}$  (for  $D = 1 \text{ mm}$ )

$$\epsilon = R_{rms} (v_{t,rms} / c)$$

# Is FEA beam coherent?...test with diffraction



- Beam potential set by sample voltage
- No additional optics ~ *relying on the small velocity spread of collimated double-gate FEA beam*



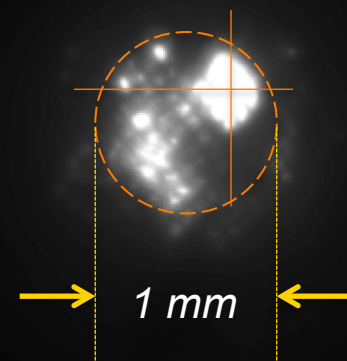
## E-diffraction from monolayer graphene

1<sup>st</sup> order  
diffraction

1keV beam

$V_{ge} = 43 \text{ V}, k_{col} = 1$

Direct beam



$R$   
 $D(1)$

2nd order  
diffraction

$$\sigma_c \sim (R/D^{(1)}) a_{gp} = 0.8 \text{ nm}$$

$$\sim (\hbar / mc) [\epsilon_x / \sigma_x]^{-1}$$

$$\Leftrightarrow \epsilon / \sigma = 0.5 \text{ } \mu\text{m/mm-rms}$$

# Ideal emittance of field emission beam?

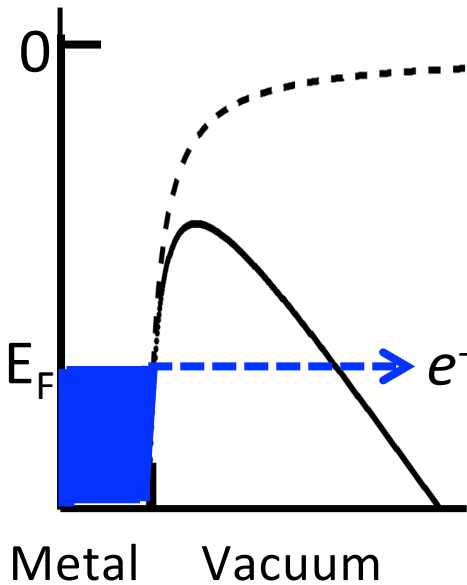
Transmission

$$\ln T(E) = -G(E) \approx -G_F + \frac{E - E_F}{d_F}$$

Field emission current (density)

$$J = \int j(E) dE$$

$$j(E) \approx j_0 e^{E/d_F} / (1 + e^{E/k_B T})$$



Average total energy

$$\langle E - E_F \rangle = \frac{\int (E - E_F) j(E) dE}{\int j(E) dE} \approx -\pi p d_F \cot \pi p$$

Average *normal* energy

$$\langle E_z - E_F \rangle = \frac{\int (E_z - E_F) j(E) dE}{\int j(E) dE} \approx -d_F [1 + \pi p d_F \cot \pi p]$$

Average *transverse* energy

$$\langle E_t \rangle = \langle E \rangle - \langle E_z \rangle \approx d_F = \frac{2}{3} \frac{F_{tip}}{\tau_F b \phi^{1/2}}$$

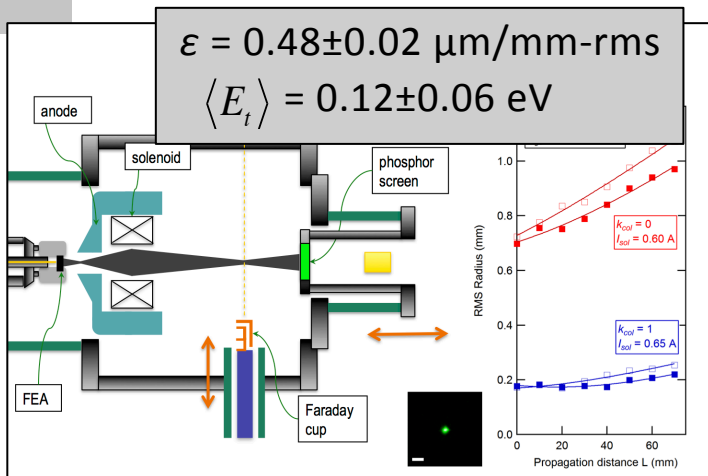
= 0.1-0.2 eV at  $F_{tip} = 2-5$  GV/m

Intrinsic transverse emittance

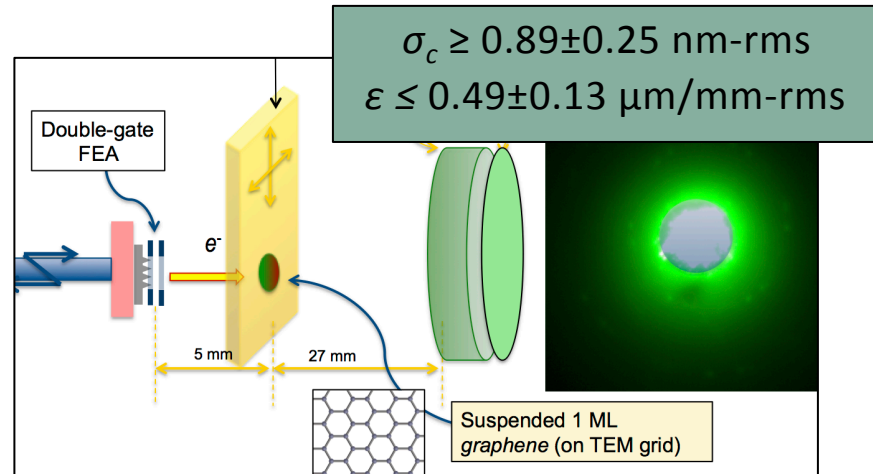
$$\varepsilon / \sigma_s = \sqrt{\frac{d_F}{mc^2}} = 0.45-0.63 \text{ } \mu\text{m/mm-rms}$$

at  $F_{tip} = 2-5$  GV/m

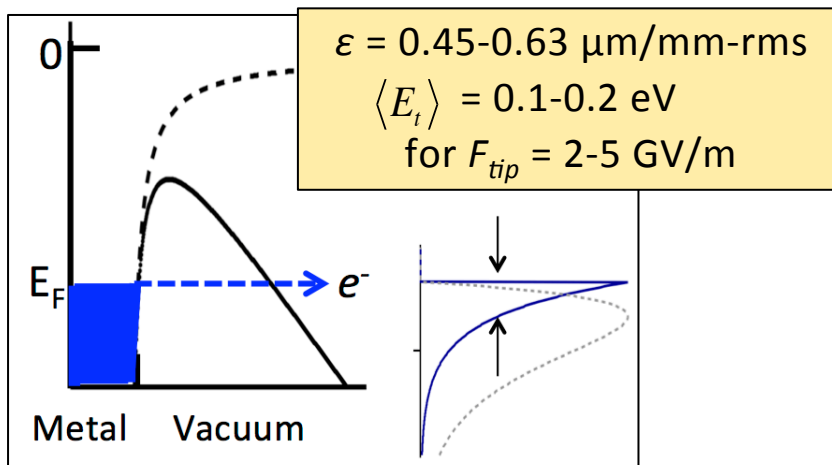
## Beam measurement



## Low-energy electron diffraction



## Electron distribution model (theory)



- Definite advantage of our double-gate FEA for applications that demands low phase space volume e-beam.
- Competitive emittances as the state-of-the-art photocathode excited by UV
- All metal nanotip array: importance of small voltage dispersion (no ballast resistors)

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## Vacuum Nanoelectronics group

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- Anna Mustonen, Dr. (former student)
- Prat Das Kanongo, Dr. (former PD)
- Youngin Oh (former PD)
- Mahta Monshipouri
- Chiwon Lee (also at MPI)
- Jens Gobrecht (LMN lab head)

## SwissFEL &amp; Accelerator Dept.

- Martin Paraliiev, Dr.
- Masamitsu Aiba, Dr.
- Hans-Heinrich Braun, Dr.
- Albin Wrulich, Prof. Dr.

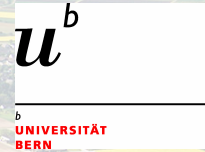
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- H. W. Fink, Prof. Dr.



## AIST, Tsukuba, Japan

- T. Yamada (CNT)



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